

Extreme-Precision MEMS Segmented Deformable Mirror (NASA Phase II SBIR)

**Michael A. Helmbrecht, Ph.D.
Iris AO, Inc.**

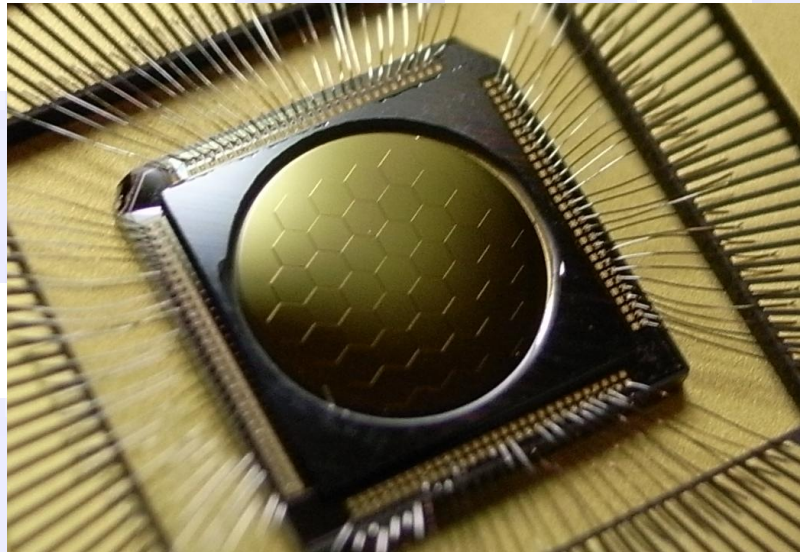
**www.irisao.com
michael.helmbrecht@irisao.com
info@irisao.com**

Mirror Technology Days

August 25th – 27th, 2008

Precision DMs & Electronics

Compact



Robust

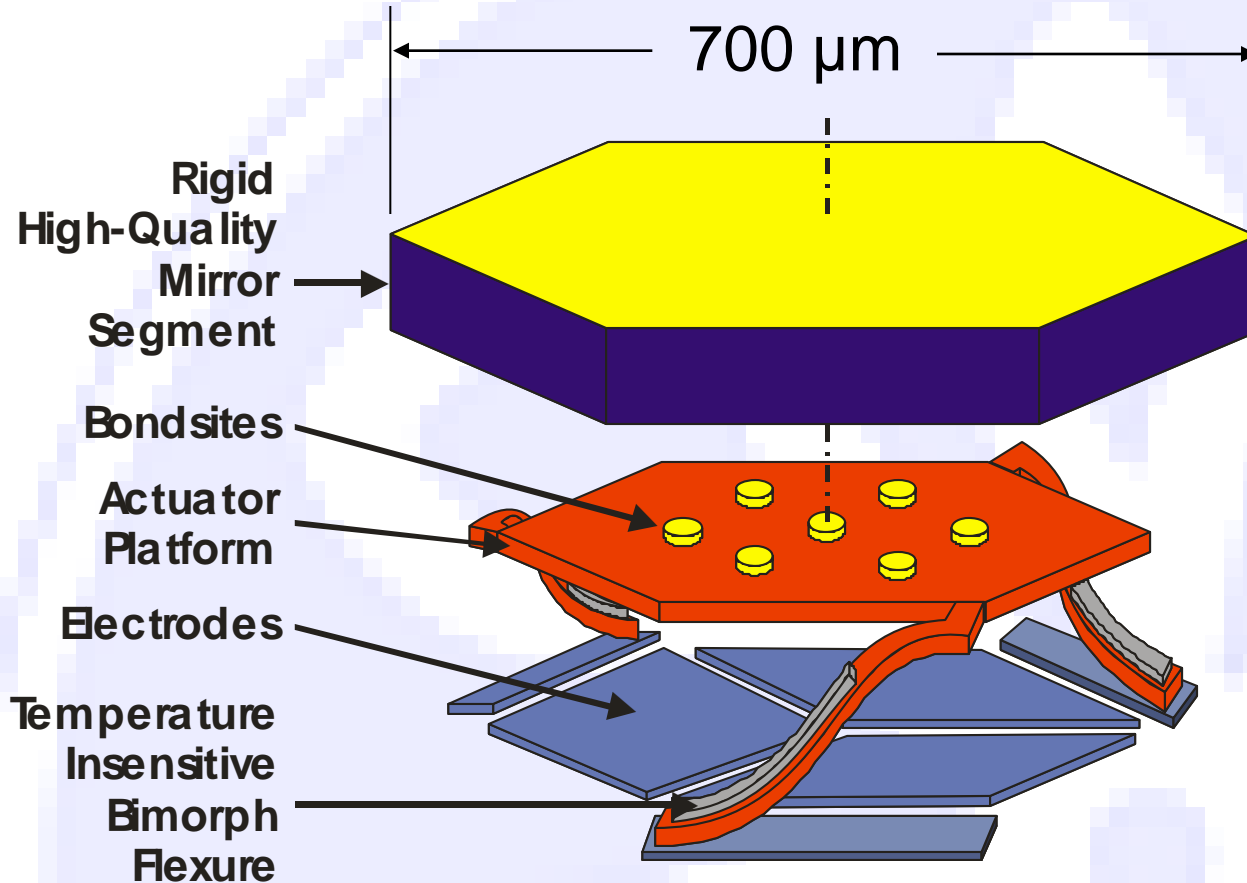
Easy to Use

Outline

- Iris AO DM Segment
- NASA Phase II SBIR Progress
 - Precision MEMS DM
 - Precision drive electronics
- DM Scaling
 - NIH Phase II SBIR Progress
 - 163 segment DM
 - 10^3 segment scaling demonstration



Segmented MEMS DM Schematic



- Robust single-crystal-silicon assembled mirror surface stays flat ($0.56 \text{ nm/}^{\circ}\text{C PV}$)
- Temperature-insensitive bimorphs elevate mirror above substrate ($14 \text{ nm/}^{\circ}\text{C}$, $\sigma=0.8 \text{ nm/}^{\circ}\text{C}$)
- Piston/tip/tilt electrostatic actuation
- 2.3 kHz frequency response
 - 170/200 μs rise/fall times, 10-90%



Phase II SBIR Goals



Performance Period: Jan 29 2007 – Jan 28, 2009

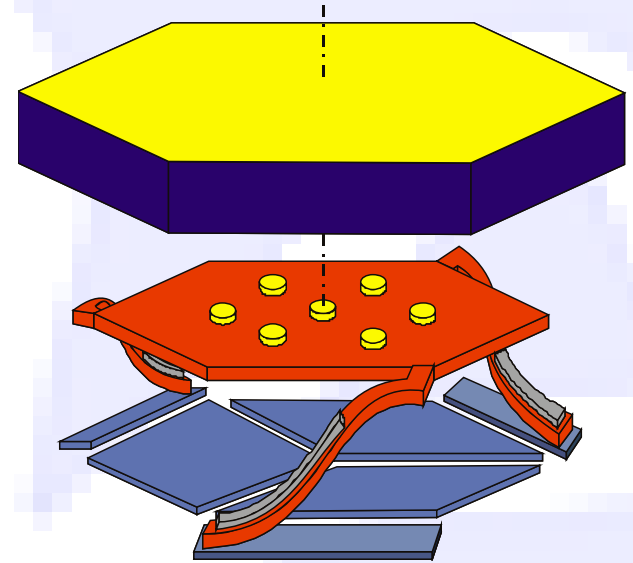
Specification	Start of Phase II	Phase II Demo Goal*	Phase II Study Goal	Today (8/2008)
Surface Figure Errors (nm <i>rms</i>)	6-20	1-3	0.1	5-11
Open-loop positioning accuracy (<i>rms</i>)	20-30 nm	10 nm	Not Specified	8 nm (flattened)
Positioning resolution (nm <i>rms</i>)	5 (elect noise limited)	0.14	0.04	0.45 (0.11 PWM)
Stability (nm <i>rms</i>) • over 15-60 min	0.2-1.2 (5 elect. noise)	0.2	0.04	TBD
Failure Testing: Continue testing and determine techniques to eliminate potential snap-in failures				

* Independent verification by the Lab for AO at UC Santa Cruz



Surface Figure Errors

- Current designs: 5-11 nm *rms*
 - Single-crystal-silicon segments
 - Segment thickness = 25 μm
- Thicker  Flatter
 - Surface figure errors  $1/t^{2-3}$
 - DMs with 50 μm -thick mirrors will be fabricated by end of contract
 - Expect 4-8X improvement in *rms* figure errors



Closed-Loop Flattened DM



Mag: 1.4 X

Mode: PSI

Surface Data

Date: 06/20/2008

Time: 16:19:29

Surface Statistics:

Ra: 6.04 nm

Rq: 7.74 nm

Rz: 55.73 nm

Rt: 69.79 nm

Set-up Parameters:

Size: 736 X 480

Sampling: 6.06 μ m

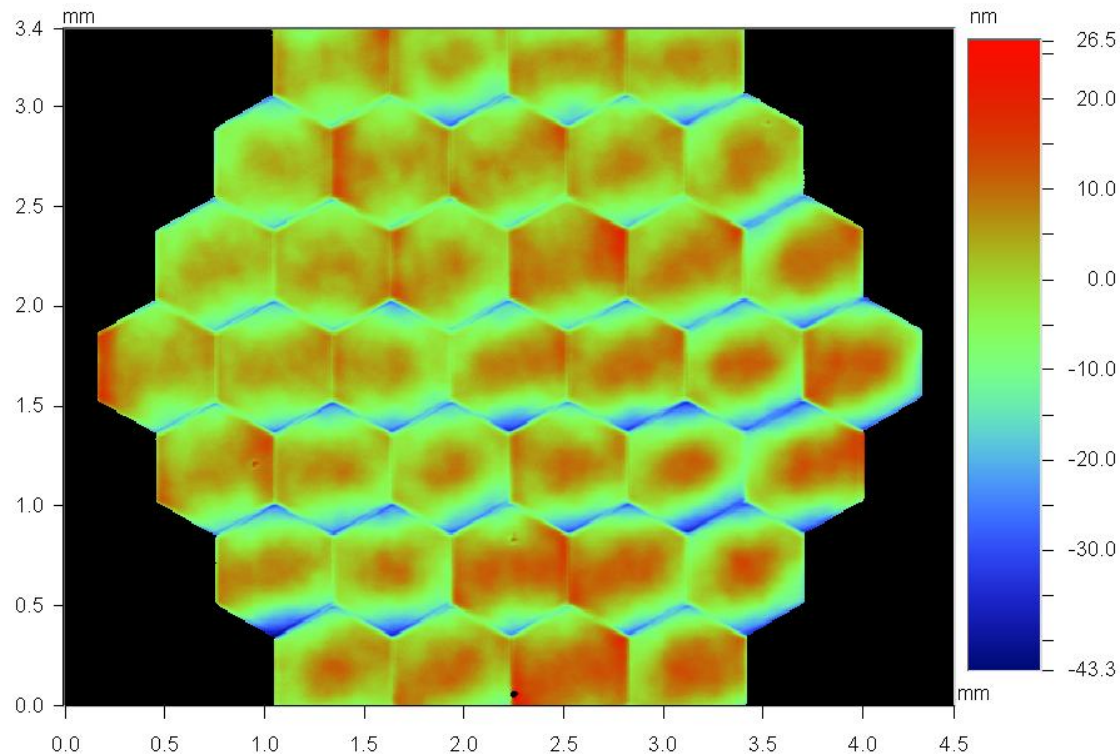
Processed Options:

Terms Removed:

Tilt

Filtering:

None



Title: FSC37-01-07-0614

Note: Closed-Loop Flattened

August 26th, 2008

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Open-Loop Flattened DM



Mag: 1.4 X

Mode: PSI

Date: 06/19/2008

Time: 16:02:01

Surface Data

Surface Statistics:

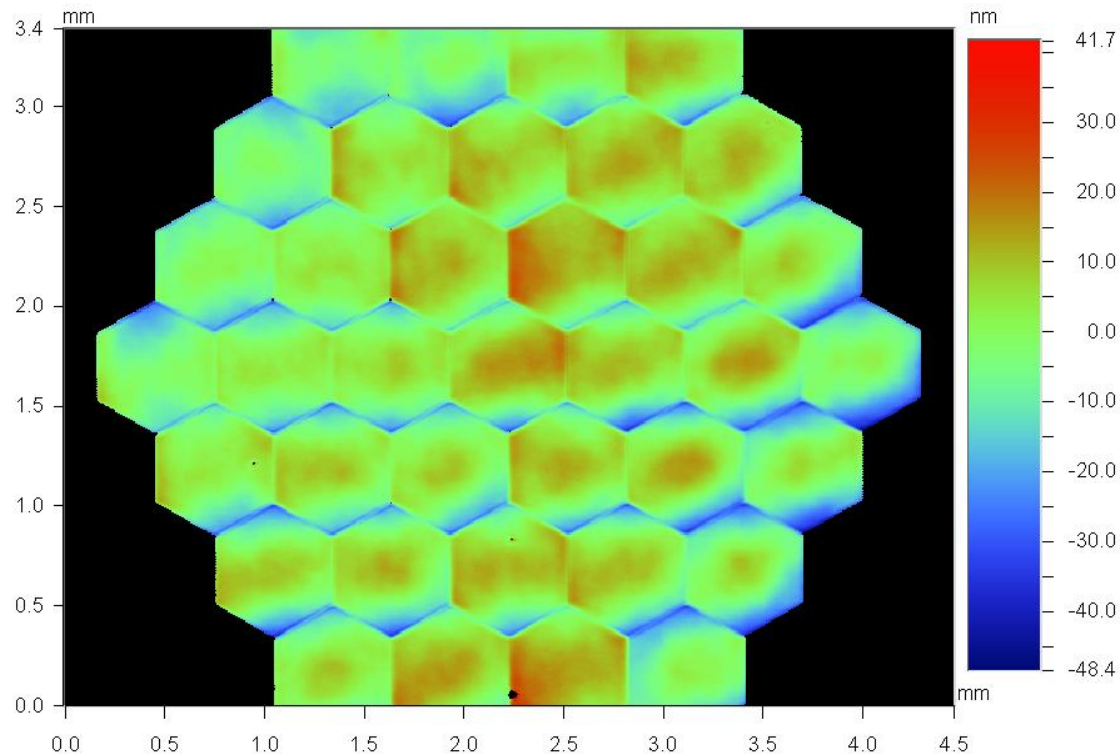
Ra: 7.28 nm
Rq: 9.21 nm
Rz: 67.65 nm
Rt: 90.05 nm

Set-up Parameters:

Size: 736 X 480
Sampling: 6.06 μ m

Processed Options:

Terms Removed:
Tilt
Filtering:
None

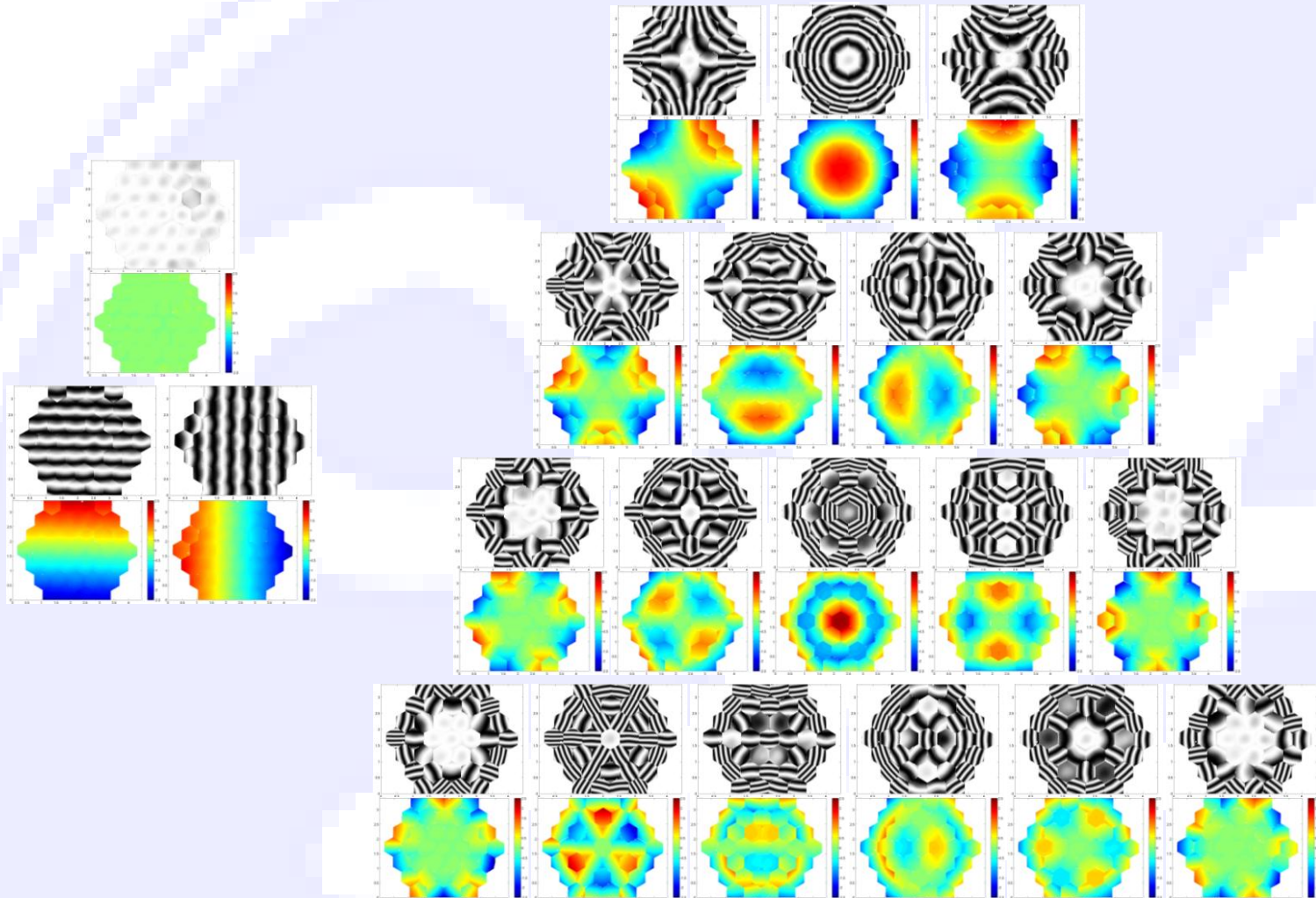


Title: FSC37-01-07-0614

Note: Open-Loop Flattened

August 26th, 2008

Open-Loop Positioning Example



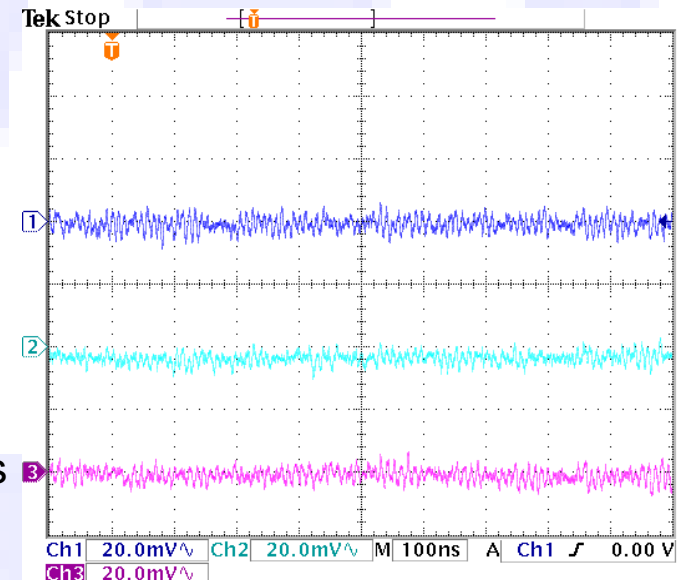


Extreme Positioning Resolution

1. DM design that uses full scale voltage
 - Actuator fabrication complete
2. Compact, low noise, high resolution electronics



- 14 bit, 200 V
- Factory calibrated with on-board calibration values
- USB interface - (Low speed 150 Hz)
- Scales to > 10k channels
- High speed interface options will be available
 - Digital input supports 35 kHz frame rate
 - Analog Output $f_{-3db} > 5$ kHz

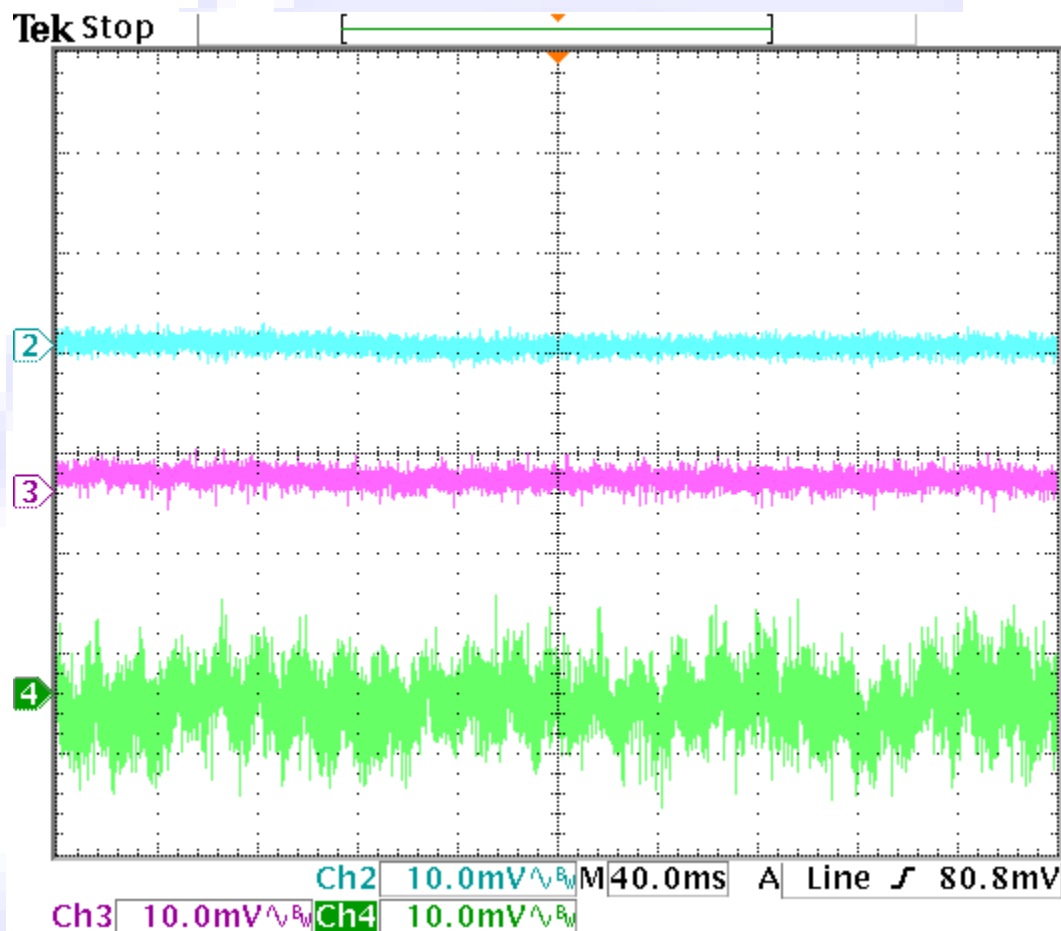


Unfiltered Noise: 3.3 mV rms



Noise Filtering

- Noise is mostly high frequency
- Low-speed applications can take advantage of filtering



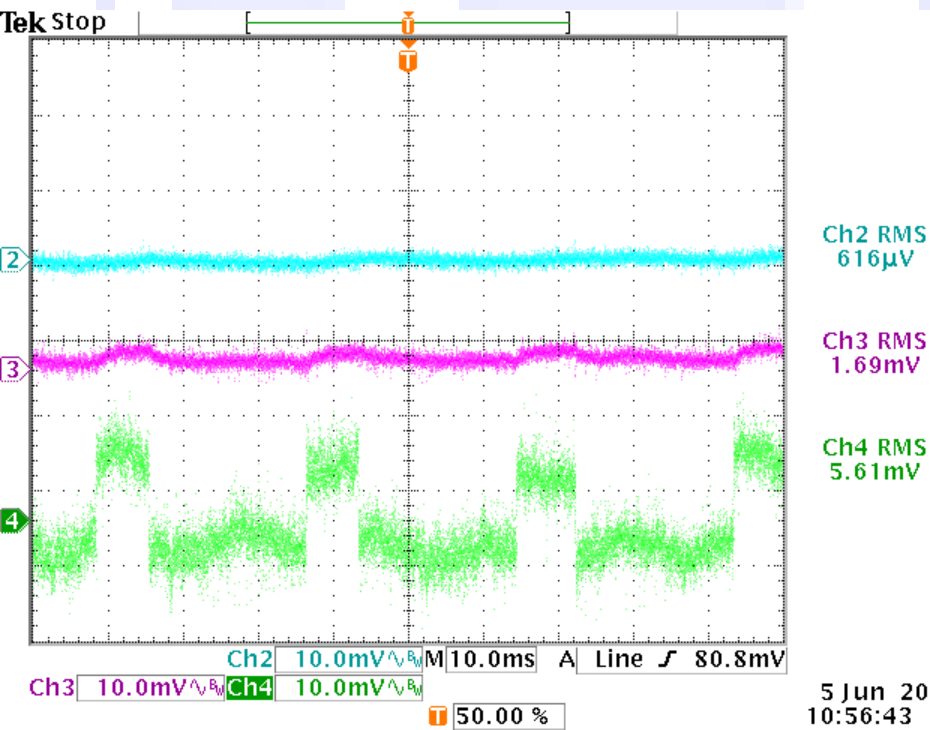
2nd Filter Output
(15.9 Hz F_{-3dB})

1st Filter Output
(15.1 Hz F_{-3dB})

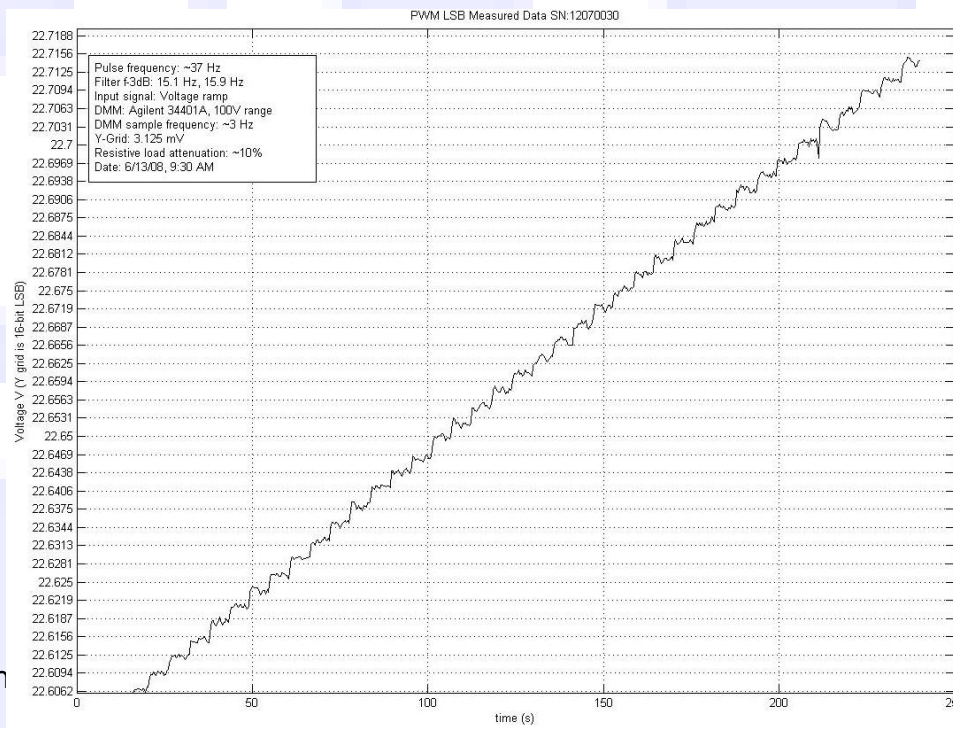
Unfiltered Output

Modulation + Filtering = Super Resolution

- LSB modulation with low-pass filtering
 - 16+ bits resolution
- First demonstration modulated at ~35 Hz shows 16-bit resolution
- >5 kHz modulation when implemented in firmware

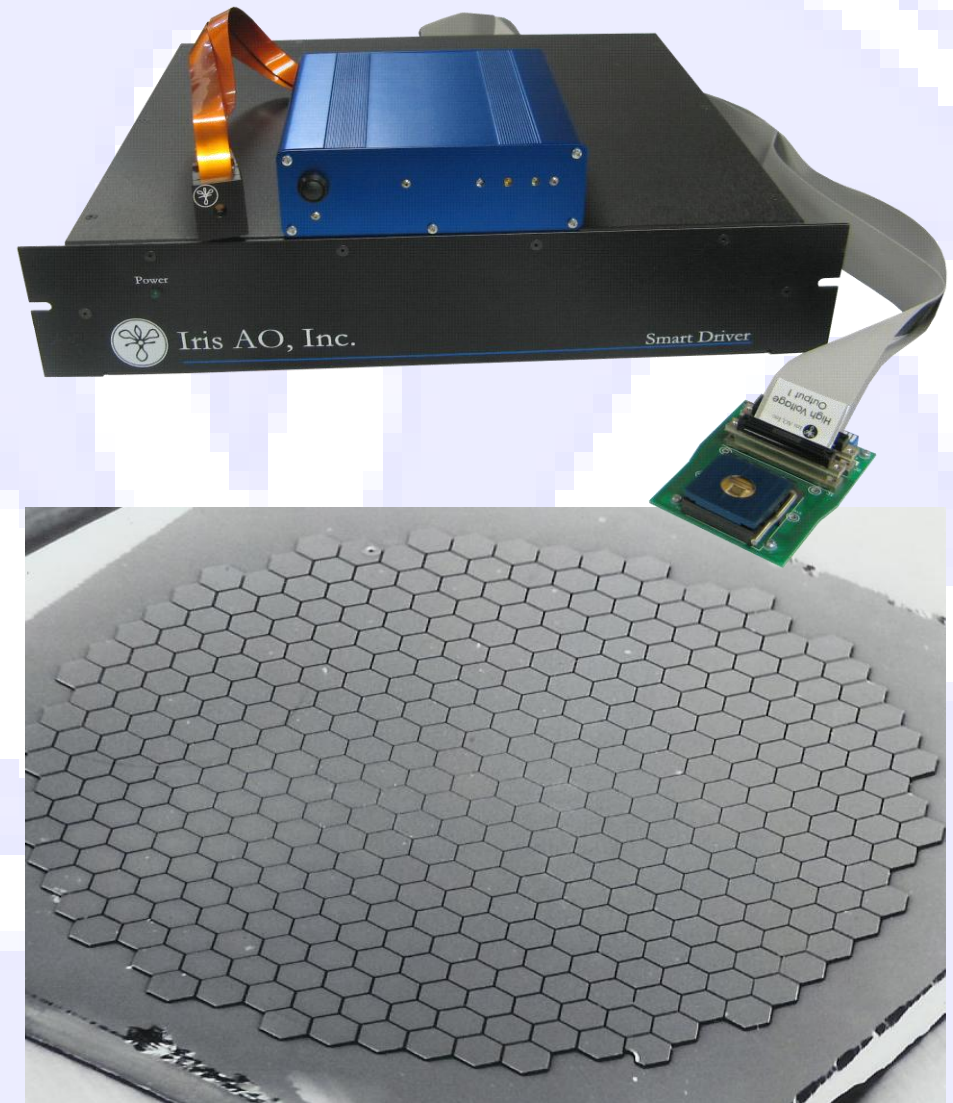


5 Jun 2008
10:56:43

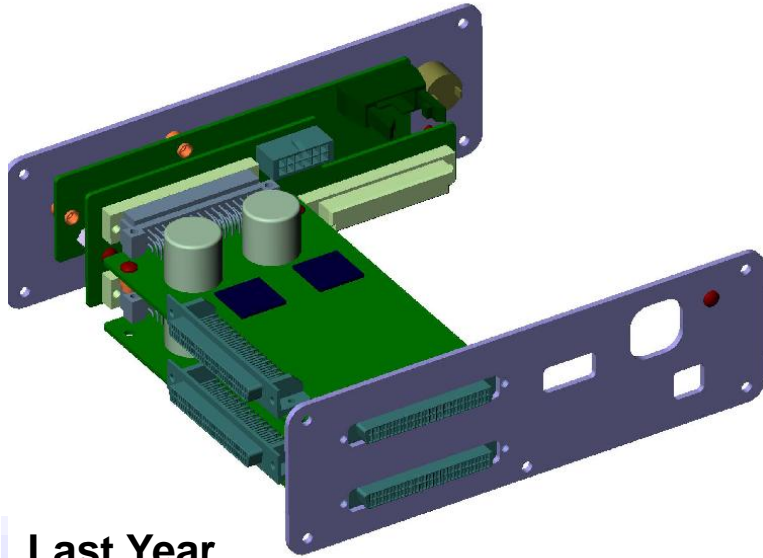


Scalability

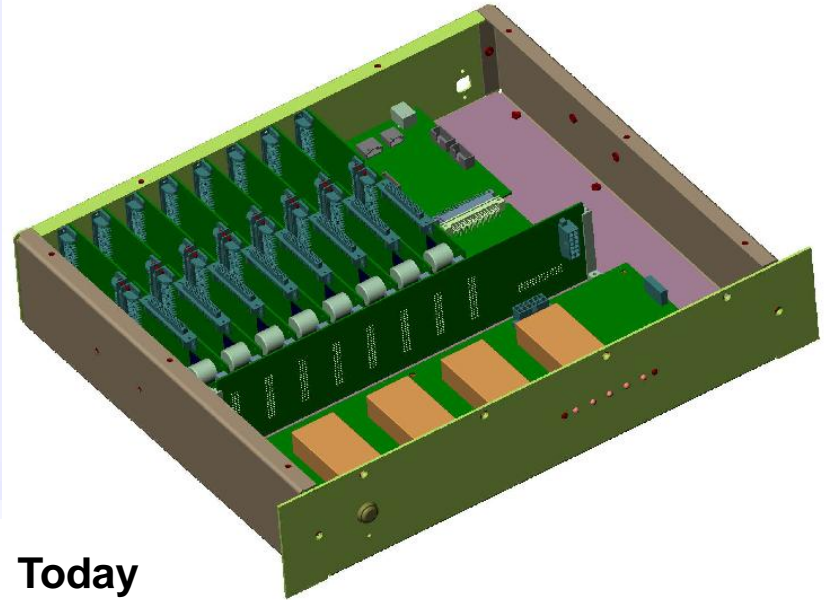
- Scalable drive electronics
 - NASA Phase II SBIR
- 163-segment DM
 - NIH Phase II SBIR
- 10^3 segment DM
 - Funding TBD
 - Preliminary experiments where possible



Smart Driver II Electronics – 512 Channels



Last Year

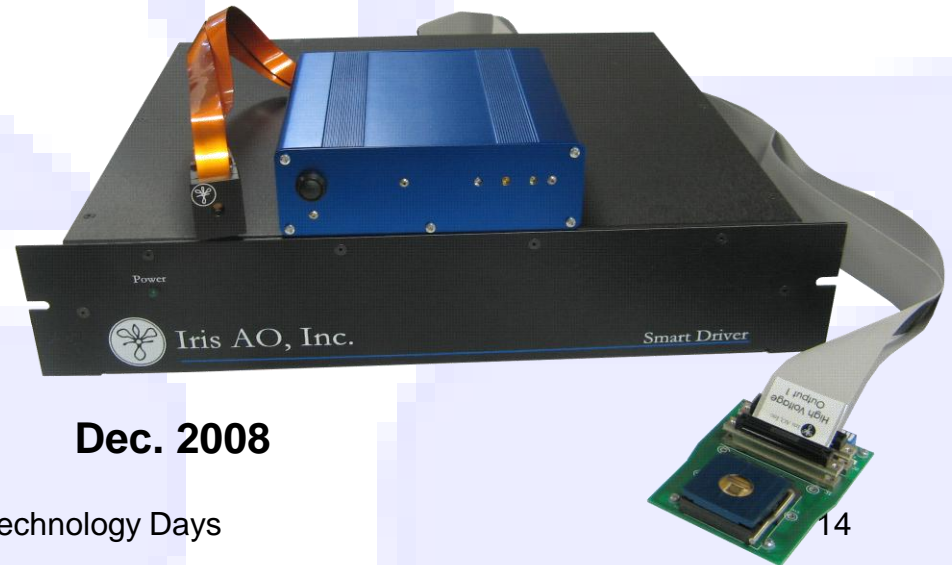


Today



Today

August 26th, 2008



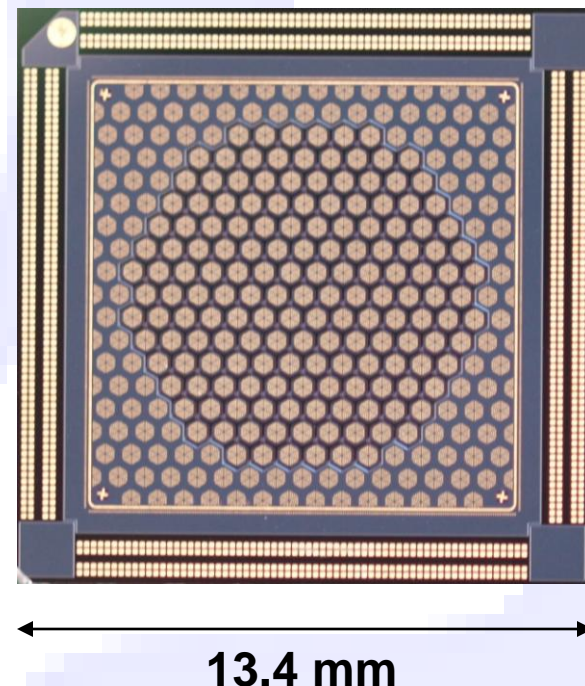
Dec. 2008

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163 Segment (S163-X) DM Development

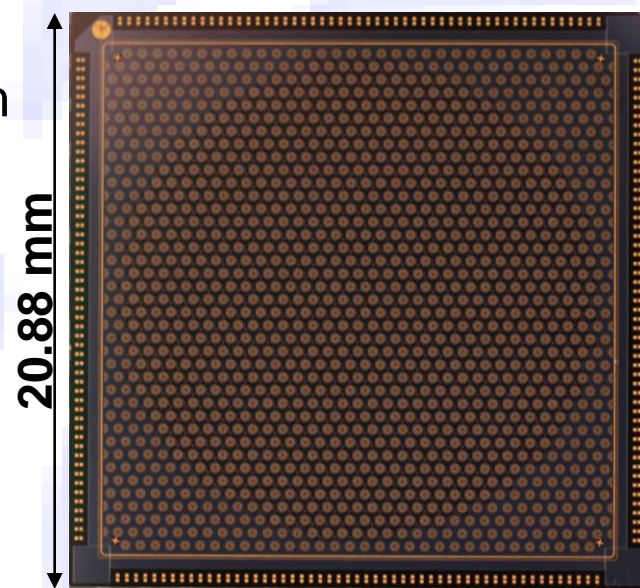
- Funded by NIH Phase II SBIR
 - Sept 2007 – August 2009
- Actuator wafer process development underway
 - 1st Run: Electrode and mechanical layer only
 - 2nd Run: Includes wiring layer
 - Fabrication begins 9/2/08
- Mirror-wafer fabrication to begin 10/2008
 - Mirror-wafer process already developed





10^3 Segment DM

- Path-finding research into 10^3 segment class DMs
- Developing along with S163-X
 - Multi-project wafer
 - 1st and 2nd fabrication runs
- 925 actuators w/ganged electrodes to reduce wiring
- Segment pitch matches EPIC point design
 - Extrasolar Planetary Imaging Coronagraph (EPIC) - Discovery Mission Concept
 - Clampin/Lyon GSFC
- Additional funding TBD
 - Proposing Phase I SBIR to NASA GSFC



Summary

- On our way to meeting Phase II SBIR goals
 - Low-noise electronics
 - Super-resolution technique
 - DM flatness improving (2X since start of contract)
 - Expect to reach 1-3 nm rms surface figure error goal
- Developing larger mirrors
 - S163-X prototype development
 - 10^3 segment DM proof-of-concept development
 - Needs additional funding to wire and package

Acknowledgements

Funding Sources



- NASA – Phase II SBIR, (Extreme Precision DM Testing and Development)
 - NNG07CA06C



- Center for Adaptive Optics (DM Process Development)
 - National Science Foundation Science and Technology: No. AST – 9876783



- National Eye Institute – Phase II SBIR (DM Process Development)
 - 2 R44 EY015381-02A1



- US Air Force – Phase II SBIR (DM Control)
 - FA8650-04-M-6518



- National Science Foundation – Phase II SBIR (Ancillary Process Development)
 - DMI-0522321

R&D Fabrication Facility



- Berkeley Microfabrication Laboratory

Research Collaboration



- Berkeley Sensor & Actuator Center